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(54) **METHOD FOR ADJUSTING CAPACITANCE OF AN ON-CHIP CAPACITOR**

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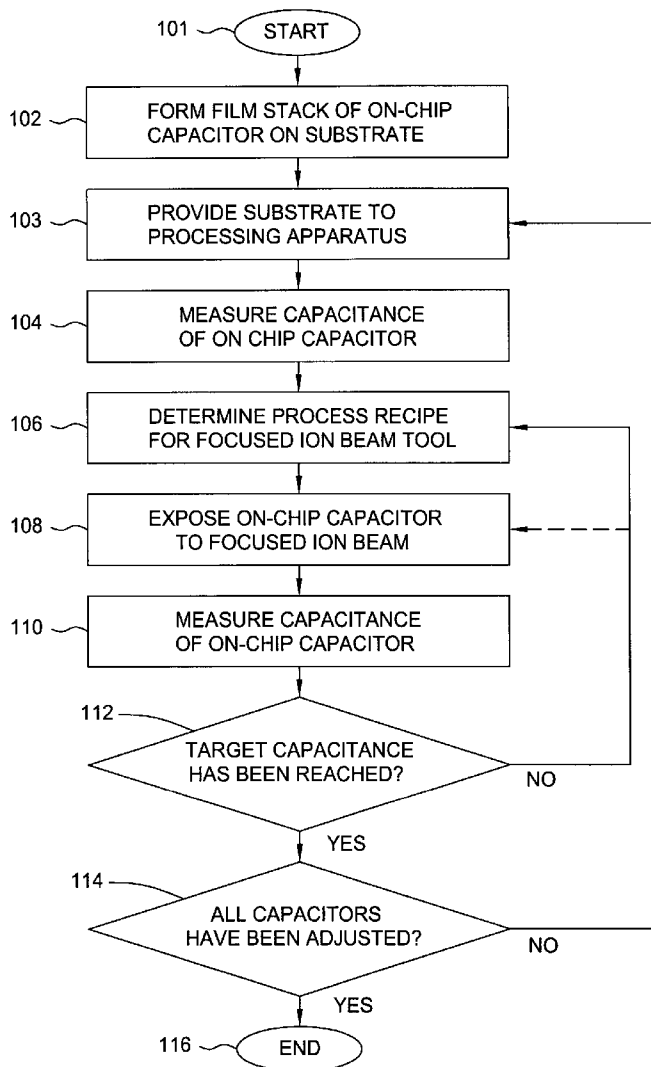
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(57) **ABSTRACT**

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A method and apparatus for adjusting capacitance of an on-chip capacitor uses exposure of a dielectric material of the capacitor to an ion beam comprising ions of at least one material to modify a dielectric constant of the dielectric material.



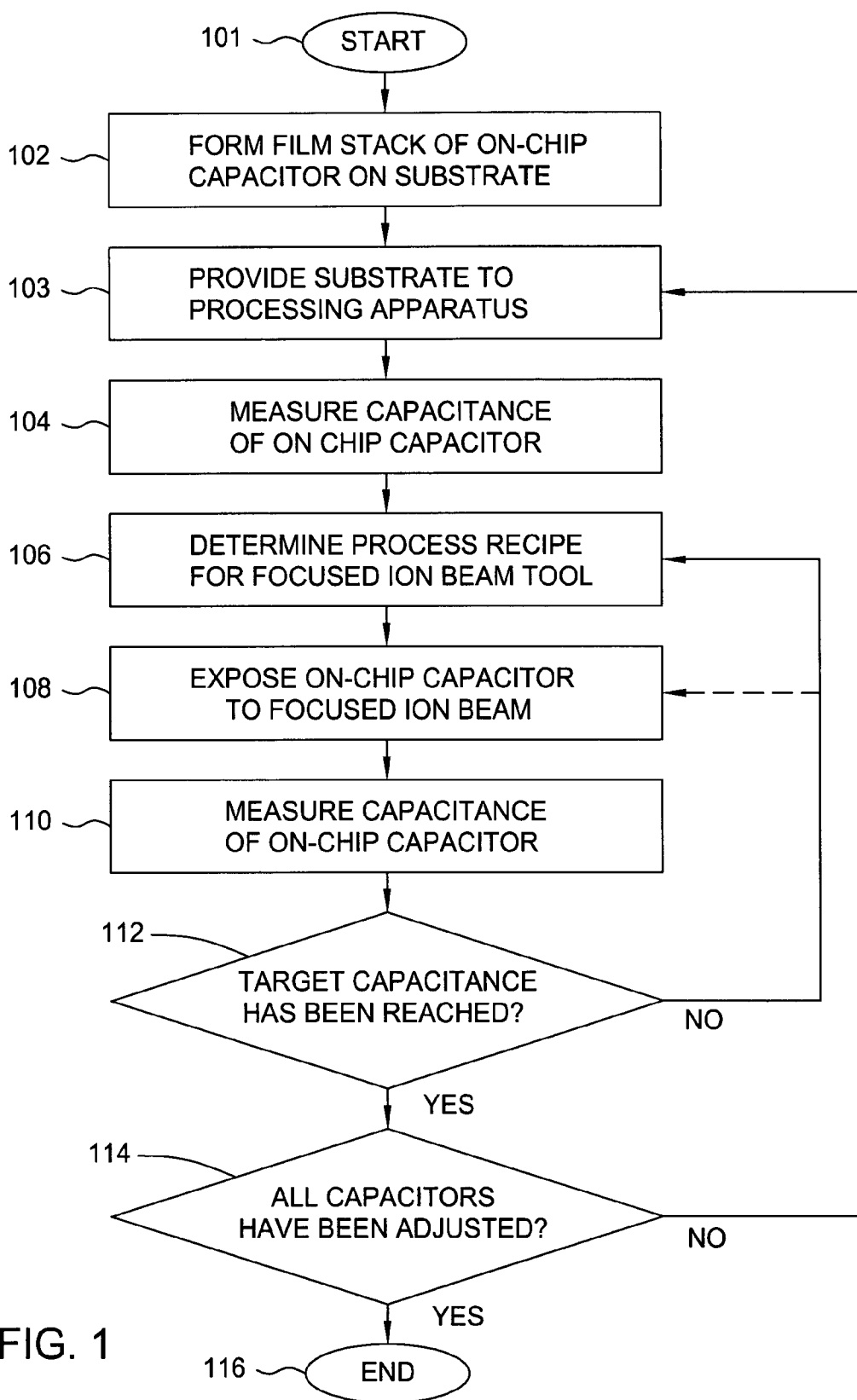


FIG. 1

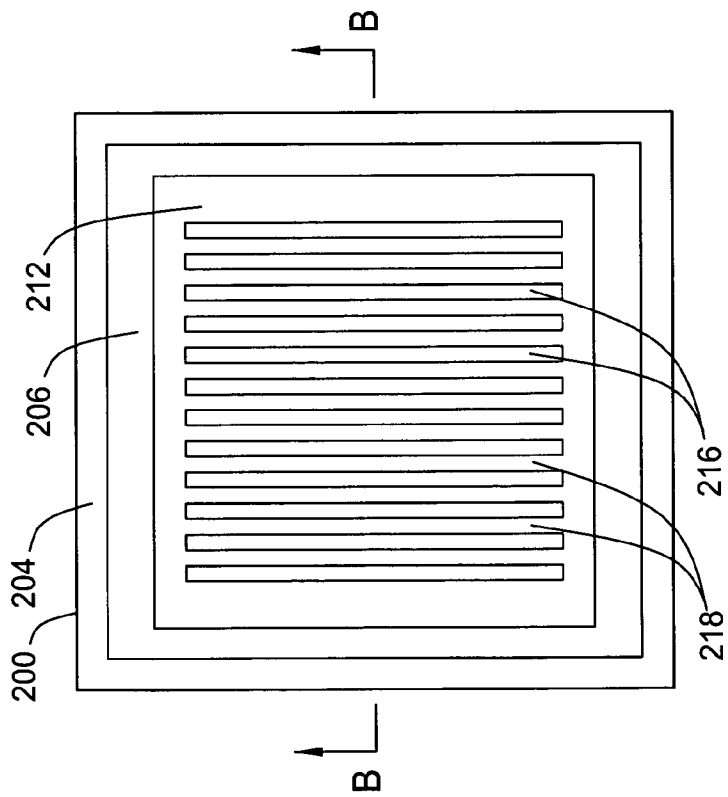


FIG. 2A

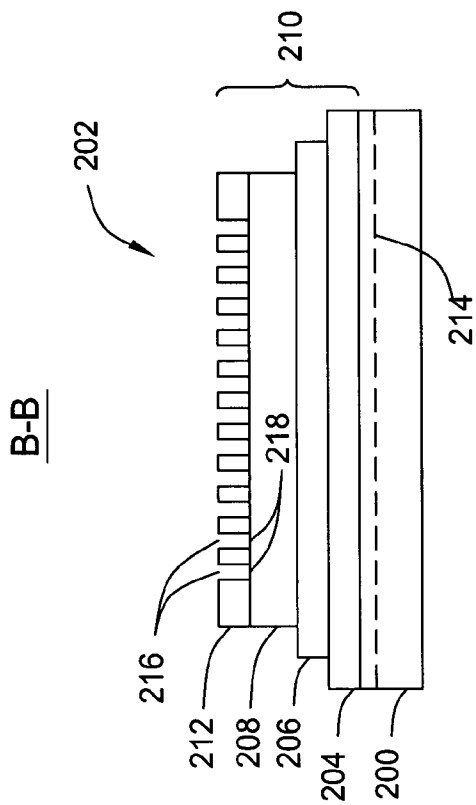


FIG. 2B

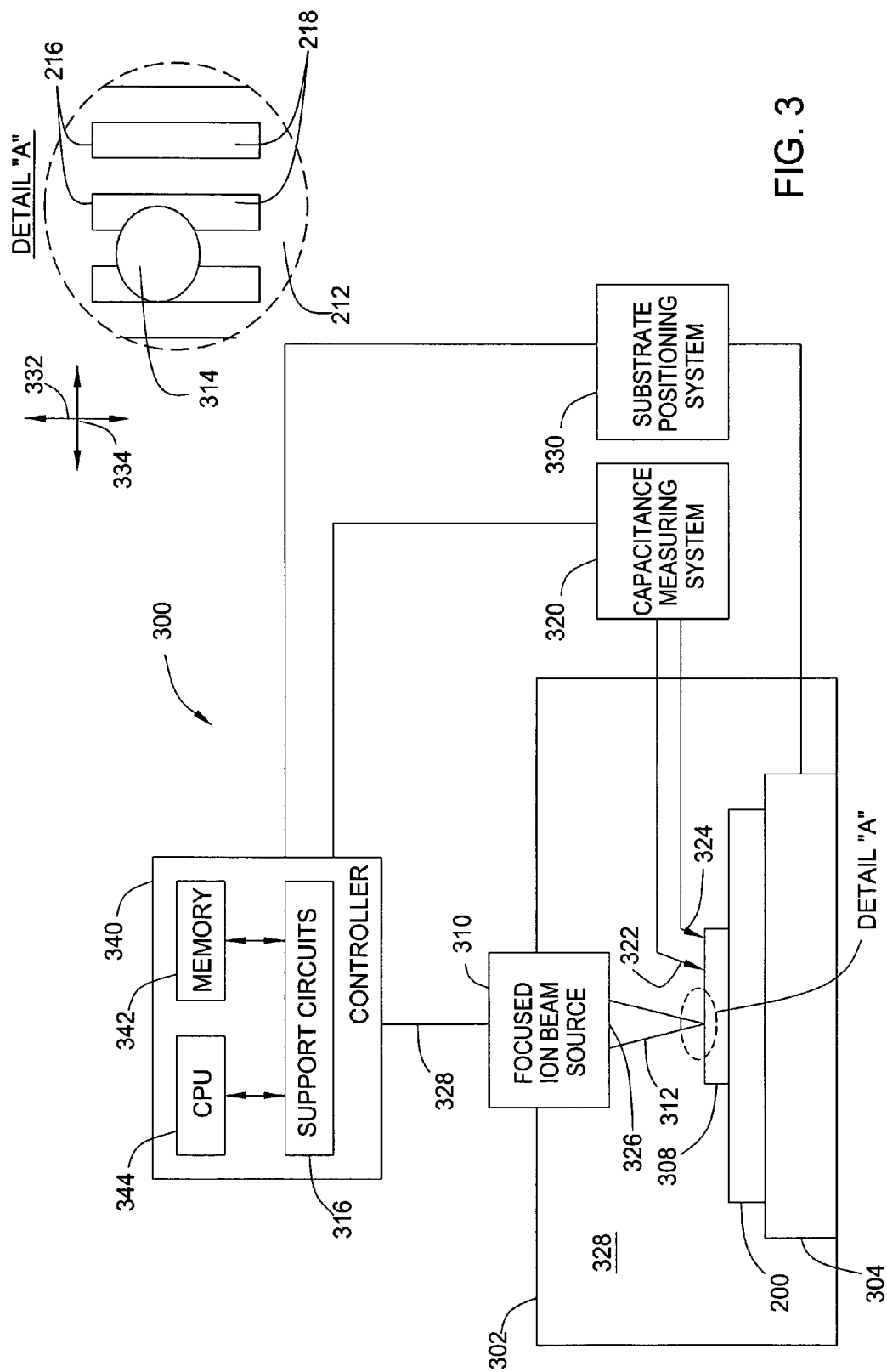


FIG. 3

METHOD FOR ADJUSTING CAPACITANCE OF AN ON-CHIP CAPACITOR

BACKGROUND OF THE INVENTION

[0001] 1. Field of the Invention

[0002] The present invention generally relates to a method for fabricating devices on semiconductor substrates. More specifically, the present invention relates to a method for adjusting capacitance of on-chip capacitors formed on a semiconductor substrate.

[0003] 2. Description of the Related Art

[0004] Advanced integrated circuits (ICs) may include more than one million micro-electronic devices that are formed on a semiconductor substrate and cooperate to perform various functions within the IC. Conventionally, ICs may use add-on precision surface-mount discrete capacitors and on-chip (i.e., thin film) capacitors. On-chip capacitors have significant integration, reliability, and cost advantages over the surface-mount discrete capacitors, particularly, in applications such as portable and mobile devices, cell phones, personal digital assistants (PDAs), and the like. However, variables of manufacturing processes may result in inaccuracy of the capacitance of on-chip capacitors.

[0005] Methods used to adjust capacitance of the on-chip capacitors include laser trimming of a capacitor to a predetermined, or target, capacitance, as well as use of on-chip trim capacitors that may be selectively disconnected from the capacitor being adjusted. Such methods require allocation on the substrate of an additional surface area for the large on-chip capacitor being then trimmed down or the trim capacitors. Furthermore, fragments of the materials dispersed across the substrate by the laser beam during processes of laser trimming the capacitor or laser cutting the conductors connecting the trim capacitors may contaminate or damage the IC.

[0006] Therefore, there is a need in the art for an improved method for adjusting capacitance of on-chip capacitors in manufacture of integrated circuits.

SUMMARY OF THE INVENTION

[0007] A method for adjusting capacitance of an on-chip capacitor using exposure of a dielectric material of the capacitor to an ion beam comprising ions of at least one material that can modify a dielectric constant of the dielectric material.

[0008] Another aspect of the invention is an on-chip capacitor comprising at least one insulative layer that separates the conductive layers, wherein the at least one insulative layer comprises a material that was exposed to an ion beam modifying a dielectric constant of the material.

[0009] Still another aspect of the invention is a method for adjusting capacitance of an on-chip capacitor in a substrate processing chamber by irradiating a dielectric material of the capacitor using an ion beam comprising ions of at least one material that can modify a dielectric constant of the dielectric material, and monitoring the capacitance of the on-chip capacitor being irradiated.

[0010] Yet another aspect of the invention is an apparatus for adjusting capacitance of an on-chip capacitor. The appa-

ratus comprises a processing chamber, a source of an ion beam for irradiating a dielectric material of the capacitor, a system for measuring capacitance of the capacitor, and a controller configured to administer operation of the apparatus.

BRIEF DESCRIPTION OF THE DRAWINGS

[0011] The teachings of the present invention can be readily understood by considering the following detailed description in conjunction with the accompanying drawings, in which:

[0012] **FIG. 1** depicts a flow diagram for a method for adjusting capacitance of an on-chip capacitor in accordance with one embodiment of the present invention;

[0013] **FIG. 2A** depicts a top plan view of a substrate having the on-chip capacitor being adjusted in accordance with the method of **FIG. 1**;

[0014] **FIG. 2B** depict a cross-sectional view of a substrate having the on-chip capacitor being adjusted in accordance with the method of **FIG. 1**; and

[0015] **FIG. 3** depicts a schematic diagram of an exemplary processing apparatus of the kind used in performing portions of the method of **FIG. 1**.

[0016] To facilitate understanding, identical reference numerals have been used, where possible, to designate identical elements that are common to the figures. It is to be noted, however, that the appended drawings illustrate only exemplary embodiments of this invention and are therefore not to be considered limiting of its scope, for the invention may admit to other equally effective embodiments.

DETAILED DESCRIPTION

[0017] The present invention is a method and apparatus for adjusting capacitance of an on-chip capacitor formed on a substrate (e.g., semiconductor wafer). The method may be used for fabricating precision and high reliability on-chip capacitors.

[0018] **FIG. 1** depicts a flow diagram for one embodiment of the inventive method **100** for adjusting capacitance of an on-chip capacitor. The method **100** includes the processes that are performed upon a film stack to adjust capacitance of the capacitor.

[0019] **FIGS. 2A and 2B** depict, respectively, schematic top plan and cross-sectional views of a substrate showing the on-chip capacitor being adjusted using the method **100**. The cross-sectional view in **FIG. 2B** is taken along a centerline B-B in **FIG. 2A**. **FIG. 3** depicts a schematic diagram of an exemplary processing apparatus of the kind used in performing one or more steps of method **100** of **FIG. 1**.

[0020] The images in **FIGS. 2A-2B** and **FIG. 3** are not depicted to scale and are simplified for illustrative purposes. To best understand the invention, the reader should simultaneously refer to **FIGS. 1, 2A-2B, and 3**.

[0021] The method **100** starts at step **101** and proceeds to step **102**. At step **102**, a film stack **210** of an on-chip capacitor **202** is formed on a substrate **200** (e.g., silicon (Si) wafer, gallium arsenide (GaAs) wafer, and the like) (See **FIGS. 2A-2B**). In one embodiment, the on-chip capacitor **202** is a precision thin film capacitor having the film stack

210 that illustratively comprises a barrier layer **204**, a bottom electrode **206**, a dielectric layer **208**, and a top electrode **212**.

[0022] The barrier layer **204** electrically isolates the bottom electrode **206** from the substrate **200** and may be formed from a dielectric material, such as silicon dioxide (SiO₂), silicon carbide (SiC), silicon nitride (Si₃N₄), and the like. The substrate **200** may comprise one or more conductive and dielectric layers disposed beneath the film stack **210**. When the substrate **200** comprises a dielectric upper film **214** (shown in phantom in FIG. 2B), the barrier layer **204** may not be needed. As such, the barrier layer **204** is considered optional.

[0023] The bottom electrode **206** and the top electrode **212** are generally formed from at least one conductive material (e.g., titanium (Ti), tantalum (Ta), tungsten (W), platinum (Pt), titanium nitride (TiN), and the like) or a conductive alloy thereof. The dielectric layer **208** is generally formed to a thickness of about 50 to 1000 Angstroms and may comprise at least one film of silicon dioxide, barium-strontium titanate (Ba,Sr)TiO₃, porous organosilicate, titanium oxide, tantalum oxide, zirconium oxide, yttrium oxide, aluminum oxide, and silicon nitride and the like.

[0024] In one exemplary embodiment, the top electrode **212** is patterned to expose portions **218** of the underlying dielectric layer **208**. In the depicted embodiment, the top electrode **212** comprises a plurality of grooves (openings) **216** that expose the portions **218**. In an alternate embodiment, the top electrode **212** may be patterned to comprise openings **216** having a different configuration, for example, circular openings, square openings, grid-like openings, and the like. Together, the openings **216** may expose about 15 to 85% of the surface area of the dielectric layer **208**. In a further embodiment (not shown), the top electrode **212** and, optionally, the bottom electrode **206**, may be partially embedded in the dielectric layer **208**. In such an embodiment, the entire surface area of the dielectric layer **208** may be exposed.

[0025] The layers comprising the film stack **210** may be deposited using thin film deposition techniques (e.g., atomic layer deposition (ALD), physical vapor deposition (PVD), chemical vapor deposition (CVD), plasma enhanced CVD (PECVD), and the like), spin on and then patterned using conventional lithographic and plasma etch processes. Manufacturing variables of such processes may result in inaccuracy of capacitance of the on-chip capacitor **202**. As such, when the on-chip capacitor **202** is formed, the capacitance of should be adjusted to a pre-determined, or target, capacitance.

[0026] At step **103**, the substrate **200** is provided to a processing apparatus **300** (E.G., FIG. 3). In one embodiment, the processing apparatus **300** comprises a vacuum chamber **302**, a capacitance measuring system **320**, a substrate positioning system **330**, and a controller **340**. The vacuum chamber **302** generally comprises a substrate pedestal **304** and a source **310** of a focused ion beam **312**. In the depicted embodiment, the source **310** is illustratively show as partially located within reaction volume **328** of the vacuum chamber **302**. Typically, a portion of source **310** that comprises an irradiating orifice **326** is positioned in the reaction volume **328**, while other portions of the source **310** (e.g., power supplies, control system, and the like) may be located external to the reaction volume.

[0027] The controller **340** facilitates control of the processing apparatus **300** and may be one of any form of general-purpose computer processor used in an industrial setting to control various processing chambers and sub-processors. The controller **340** generally comprises a central processing unit (CPU) **344**, a memory **342**, and support circuits **316**. The memory **342** may be in one or more forms of digital storage (e.g., electronic memory, a magnetic or optical disk, and the like), local or remote. The support circuits **316** may include cache, power supplies, clock circuits, input/output circuitry, and the like. In one embodiment, the inventive method is stored in the memory **342** as a software routine. Alternatively, the software routine may also be stored and/or executed by other CPU (not shown) that is remotely located from the hardware being controlled by the controller **340**.

[0028] In the vacuum chamber **302**, the substrate **200** is placed on the substrate pedestal **304**. In one embodiment, the substrate positioning system **330** is coupled, in a conventional way, to the substrate pedestal **304** to define the location (i.e., topographic coordinates) of the on-chip capacitor **202** on the substrate **200**. The substrate positioning system **330** may use, for example, lithographic marks, as well as other reference marks on the substrate **200** to locate the on-chip capacitor **202**. In operation, topographic coordinates of the on-chip capacitor **202** are used in the processing apparatus **300** for positioning of the on-chip capacitor, for positioning of electrical probes **322** and **324** for the capacitance measuring system **320**, and for controlling of a focal point of the focused ion beam **312**. In one exemplary embodiment, the substrate positioning system **330** positions the on-chip capacitor **202** at a pre-determined location with respect to the focal point of the focused ion beam **312**. Alternatively, the on-chip capacitor **202** may be positioned at the pre-determined location with respect to the electrical probes **322**, **324**.

[0029] At step **104**, capacitance of the on-chip capacitor **202** is measured using the capacitance measuring system **320**. In the depicted embodiment, the measurements are performed in-situ (i.e., in the vacuum chamber **302**) using electrical probes **322** and **324** that are engaged to contact the bottom electrode **206** and top electrode **212**, respectively. The results of the measurements are communicated to the controller **340** for analysis.

[0030] In an alternative embodiment, the capacitance of the on-chip capacitor **202** may be measured ex-situ before the substrate **200** is placed in the vacuum chamber **302**. After the measurements, the substrate is provided to the chamber and positioned on the substrate pedestal **304**, as described above in reference to step **103**.

[0031] At step **106**, the controller **340** analyses a difference between the measured capacitance of the on-chip capacitor **202** and the target capacitance of that capacitor and defines parameters of a process recipe for the source **310** of the focused ion beam **312**. In other words, the controller may select different parameters in formulating the process of irradiating the on-chip capacitor. When executed in the processing apparatus **300**, such a process recipe facilitates adjusting a starting capacitance (i.e., the capacitance measured at step **104** above) of the on-chip capacitor **202** to the target capacitance. In one embodiment, to define the parameters of the process recipe, the controller **340** may use data

that is collected on the test substrates comprising the on-chip capacitors 202. Such collection may include measurements of dependence of the capacitance from chemical composition, concentration, and intensity of the focused ion beam 312, dimensions of a spot 314 irradiated by the focused ion beam 312 on the on-chip capacitor, material of the dielectric layer 208, process time duration, and the like.

[0032] It should be noted that the present invention also provides the ability to reverse the effect of the induced change. Namely, for example, fluorine atoms can be added or removed from the thin film by changing the chemistry and environment of the ion beam process. This reversible aspect is an advantage over physical trimming. For example, it has been shown that one can increase the dielectric constant of a porous organic silicate by exposing it to an oxygen plasma, and the effect can be reversible by treating it with furnace degassing, or TMCS (tetramethylchlorosilane) with or without additional hydrogen plasma treatment.

[0033] In an alternate embodiment, the processing apparatus 300 may operate the source 310 using a pre-selected process recipe (discussed below in reference to step 110). In such an embodiment, step 106 is considered optional. During the irradiating process of step 108 below, the changes in the capacitance of the on-chip capacitor 202 are monitored in real time until the target capacitance is achieved.

[0034] At step 108, the source 310 irradiates the on-chip capacitor 202 using the focused ion beam 312 (FIG. 3). The beam 312 comprised ions of at least one material that can modify (i.e., change) a dielectric constant of a material of the dielectric layer 208 by altering the chemical composition of the material. In the depicted embodiment, the focused ion beam 312 penetrates through the openings 216 in the top electrode 212 and dopes the portions 218 of the dielectric layer 208, thereby modifying the dielectric constant of the material of the dielectric layer and changing the capacitance of the on-chip capacitor 202.

[0035] In one embodiment, the focused ion beam 312 may only irradiate a small surface area of the top electrode 212 (FIG. 3, detail "A"). However, the present invention is not so limited.

[0036] In another embodiment, the focused ion beam 312 may scan across the surface area of the top electrode (illustrated using arrows 332, 334) to irradiate the portions 218 of the dielectric layer 208 outside the spot 314. Scanning of the beam may be facilitated using beam controls of the source 310. Alternatively, the position of the spot 314 may be fixed, while the substrate positioning system 330 engages the substrate 200 in a reciprocating motion to facilitate irradiation of the exposed portions 218. In a further embodiment, both the source 310 and system 330 may participate in moving the spot 314 across the top electrode 212 to irradiate the portions 218.

[0037] The source 310 produces the focused ion beam 312 in accordance with the process recipe defined at step 106 above. In one exemplary embodiment, the focused ion beam 312 comprises ions of fluorine (F) and is used to decrease the dielectric constant of the silicon dioxide (SiO₂) dielectric layer 208. In another exemplary embodiment, the focused ion beam 312 comprising ions of oxygen (O) is used to increase the dielectric constant of the barium-strontium titanate (Ba,Sr)TiO₃ dielectric layer 208. In one embodiment, nitrogen can be used as well.

[0038] At step 110, the capacitance measuring system 320 measures capacitance of the on-chip capacitor 202 having the dielectric layer 208 irradiated using the focused ion beam 312. The results of these measurements are communicated to the controller 340 for analysis. In one embodiment, the capacitance measuring system 320 performs real-time measurements of the capacitance when the on-chip capacitor 202 is being irradiated by the focused ion beam 312. Alternatively, the capacitance of the on-chip capacitor 202 may be periodically measured during time intervals when the source 310 is temporarily disabled.

[0039] At step 112, the method 100 queries if the capacitance of the on-chip capacitor 202 has been adjusted to the target capacitance. If the query of step 112 is negatively answered, in one embodiment, the method 100 proceeds to step 106 to modify the parameters of the process recipe for the source 310 (e.g., increase or decrease in the focused ion beam 312 concentration of ions that can change the dielectric constant of the material of the dielectric layer 208, use ions of a different material, and the like). In another embodiment (shown in phantom in FIG. 1), the method 100 proceeds to step 108 to continue irradiating the dielectric layer 208 using the process recipe defined at step 104 above until the target capacitance is achieved.

[0040] If the query of step 112 is affirmatively answered, the method 100 proceeds to step 114. At step 114, the method 100 queries if, on the substrate 200, capacitance of all on-chip capacitors 202 has been adjusted as discussed above in reference to steps 103-112. If the query of step 114 is negatively answered, the sequence 100 proceeds to step 103 to locate next on-chip capacitor. If the query of step 114 is affirmatively answered, the method 100 proceeds to step 116. At step 116, the method 100 ends.

[0041] While the foregoing is directed to the illustrative embodiment of the present invention, other and further embodiments of the invention may be devised without departing from the basic scope thereof, and the scope thereof is determined by the claims that follow.

1. A method for adjusting capacitance of an on-chip capacitor, comprising the steps of:

providing the on-chip capacitor, wherein the on-chip capacitor has at least one material layer having a dielectric constant that defines a capacitance of the on-chip capacitor; and

exposing said at least one material layer to an ion beam comprising ions of at least one material, thereby modifying the dielectric constant of said at least one material layer to effect a change in said capacitance of the on-chip capacitor.

2. The method of claim 1, wherein said at least one material layer is comprised of at least one of silicon dioxide (SiO₂), barium-strontium titanate (Ba,Sr)TiO₃, porous organosilicate, titanium oxide, tantalum oxide, zirconium oxide, yttrium oxide, aluminum oxide, and silicon nitride.

3. The method of claim 1, wherein said at least one material comprises at least one of fluorine (F₂), oxygen (O₂), and nitrogen.

4. The method of claim 1, wherein said ion beam is a focused ion beam having a controlled concentration of ions.

5-8. (Cancelled)

9. A method for adjusting capacitance of an on-chip capacitor formed on a substrate, comprising the steps of:

providing the substrate to a substrate processing chamber having a substrate support pedestal and a substrate positioning system;

irradiating a dielectric material of the on-chip capacitor using an ion beam comprised of ions, thereby modifying a dielectric constant of said dielectric material to effect a change in a capacitance of the on-chip capacitor; and

monitoring said capacitance of the on-chip capacitor.

10. The method of claim 9, wherein said dielectric material comprises at least one of silicon dioxide (SiO_2), barium-strontium titanate (Ba,SrTiO_3), porous organosilicate, tita-

nium oxide, tantalum oxide, zirconium oxide, yttrium oxide, aluminum oxide, and silicon nitride.

11. The method of claim 9, wherein said ion beam comprises at least one of fluorine (F_2), oxygen (O_2), and nitrogen.

12. The method of claim 9, wherein said ion beam is a focused ion beam having a controlled concentration of ions.

13. The method of claim 9 wherein said irradiating step is implemented in accordance with at least one processing parameter, wherein said at least one processing parameter defines a concentration of said ions, an Intensity of said ion beam, or a time duration of applying said ion beam.

14-18. (Cancelled)

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